Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	101	NA adj aperture	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/07 13:49
S2	18	NA adj aperture and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/07/22 13:29
S3	267	electron adj beam and (mask or reticle) adj inspection	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 19:35
S4	18	electron adj beam and (mask or reticle) adj inspection and shaping adj aperture	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/07/22 13:41
S5	2	"20030155509"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/07/22 13:56
S6	2	"20020088940"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/07/22 14:22
S7	164	electron adj beam and (mask or reticle) adj inspection and (transmission or transmitted)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 16:37
S8	40	electron adj beam and (mask or reticle) adj inspection and (transmission or transmitted) and (shap$3 WITH aperture)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/07/22 15:12
S9	45	electron adj beam and ((mask or reticle) adj inspect$3) and (transmission or transmitted) and (shap$3 WITH aperture)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/07/22 16:06
S10	67	electron adj beam and ((mask or reticle) adj inspect$3) and (shap$3 WITH aperture)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/07/22 16:07
S11	2	"20040159787"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 19:32
S12	2	"20030155509"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/16 18:32
S13	2	"20020088940"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/16 18:40

S14	7	"6365897"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/20 20:20
S15	4	"6310341"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/16 18:43
S16	6	"5923034"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/20 20:20
S17	6	"5923034"	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 14:26
S18	1	leybourne.xa. and load adj lock	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 16:38
S19	64	leybourne.xa.	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 16:42
S20	7931	electron adj (source gun) and aperture	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 16:44
S21	930	(electron adj (source gun) and aperture) and collimat$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/06/19 12:19
S22	244	((electron adj (source gun) and aperture) and collimat$3) and inspect$3	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 16:46
S23	55	(((electron adj (source gun) and aperture) and collimat$3) and inspect$3) and NA	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 17:23
S24	2220	cluster adj tool	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 17:37
S25	302	(cluster adj tool) and (sem or stem or tem)	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 17:25
S26	100	(cluster adj tool) and tem	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 17:25
S27	22	(cluster adj tool) and tem and load adj lock	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2004/09/21 17:26

S28	238	cluster adj tool and inspect$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 17:37
S29	1	cluster adj tool and inspect$3 and tem	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 17:41
S30	94	(inline or in adj line) adj inspecti$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 17:43
S31	6	((inline or in adj line) adj inspecti$2) and TEM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 17:52
S32	3	wafer adj inspecti$2 near7 cluster adj tool	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 17:54
S33	83	electron adj gun and lab6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/21 19:35
S34	7	(electron adj gun and lab6) and space adj charge adj limit$5	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/22 11:45
S35	14	US-4911103-$.DID. OR US-4991705-$.DID. OR US-5422486-$.DID. OR US-5430292-$.DID. OR US-5692224-$.DID. OR US-5344750-$.DID. OR US-5614026-$.DID.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/22 11:45
S43	9037	inspection and (project$3 near4 image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/07 11:47
S45	1882	S43 and electron adj beam	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/07 11:49
S47	1452	S45 and (stencil or mask)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/07 11:50
S48	232	S47 and membrane	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/07 11:51
S49	43	S48 and shaping adj aperture	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/07 11:52

S50	3	S49 and collimated	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/07 11:53
S51	465852	reticle or mask	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/07 13:49
S53	2139	S51 near inspect$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/07 13:50
S54	581	S53 and detector	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/07 14:02
S55	60	S54 and detector near4 transmitted	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 14:47
S56	344	S54 and project$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/07 14:08
S57	44	S55 and project$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/09 17:01
S58	2	"20040159787"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/09 17:01
S59	2	"20030081724"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/10 15:03
S60	0	"is illustrated in FIG. 6. "	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/17 10:41
S61	0	"6087667.pn.."	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/17 16:46
S62	0	"6087667.pn."	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/17 16:46

S63	2	"20040159787"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/17 16:57
S64	11	"6040971"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/17 16:58
S65	122	Martenson.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/17 17:00
S66	0	Martenson.in. and SEM	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/17 16:59
S67	1	"multiple channel SEM"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/17 17:01
S68	593	projection adj3 lens and doublet	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/18 14:42
S69	593	S68 and doublet	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/18 14:43
S70	121	S69 and detector	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/18 14:44
S71	52	S70 and transmission	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/18 14:46
S72	1689909	S71 ande (sample reticle mask)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/18 14:46
S73	41	S71 and (sample reticle mask)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB	OR	ON	2005/06/18 14:47
S74	156	(electron adj (source gun)) and principal adj plane	US-PGPUB; USPAT; EPO; JPO; DERWENT ; IBM_TDB	OR	OFF	2005/06/19 12:20

S75	15	S74 and cross adj3 over	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 12:56
S78	54241	electron adj microscope	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 13:01
S80	2441	lens near3 doublet	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 13:01
S81	38	S78 and S80	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 13:24
S82	2	"5923034".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 13:24
S83	467883	reticle or mask	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 14:48
S84	2160	S83 near inspect$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 14:48
S85	589	S84 and detector	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 14:48
S86	4	S85 and detector near4 transmitted and scintillator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 14:55
S87	32	S84 and scintillator	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:20
S88	1	S84 and eb-ccd	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:31
S89	301	S84 and ccd	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:35
S90	214	S84 and ccd and @py<="2003"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:37

S91	168	S84 and ccd and @py<="2002"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:42
S92	53	S84 and ccd and @py<="2002" and electron adj beam	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:53
S93	2	S84 and mcp and @py<="2002" and electron adj beam	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:56
S94	2	S84 and mcp$4 and @py<="2002" and electron adj beam	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:57
S95	0	S84 and $3tdi and @py<="2002" and electron adj beam	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 15:58
S96	6	S84 and $3tdi and electron adj beam	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 16:49
S97	2	"5557105".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/06/19 16:50
S98	14	electron adj beam and (mask or reticle) adj inspection and space adj charge	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 19:40
S99	8	electron adj beam and (mask or reticle) adj inspection and thermionic	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/06/19 19:40